

## ELECTRICAL SPECIFICATIONS

<b>Nominal Frequency</b>	16.000MHz
<b>Initial Tolerance</b>	±1.0ppm Maximum (Measured at nominal Vdd and Vc; at 25°C)
<b>Frequency Stability</b>	±100ppb Maximum (Measured at nominal Vdd and Vc)
<b>Frequency Stability vs. Input Voltage</b>	±50ppb Maximum (Vdd ±5%)
<b>Frequency Stability vs. Load</b>	±50ppb Maximum (Vload ±5%)
<b>Frequency Stability vs. Aging (1 Day)</b>	±30ppb Maximum (after 72 hours of operation)
<b>Frequency Stability vs. Aging (1 Year)</b>	±500ppb Maximum (after 72 hours of operation)
<b>Frequency Stability vs. Aging (10 Years)</b>	±3.0ppm Maximum (after 72 hours of operation)
<b>Operating Temperature Range</b>	0°C to +50°C
<b>Supply Voltage</b>	5.0Vdc ±5%
<b>Warm Up Time</b>	3 Minutes Maximum (Referenced to ±500ppb of final frequency at 1 hour at 25°C)
<b>Power Consumption</b>	1.6 Watts Maximum at Steady State 2.5 Watts Maximum during Warm Up (Measured at 25°C)
<b>Output Voltage Logic High (Voh)</b>	Vdd-0.5Vdc Minimum (IOH = -8mA)
<b>Output Voltage Logic Low (Vol)</b>	0.5Vdc Maximum (IOL = +8mA)
<b>Rise/Fall Time</b>	6nSec Maximum (Measured at 20% to 80% of waveform)
<b>Duty Cycle</b>	50 ±5(%) (Measured at 50% of waveform)
<b>Load Drive Capability</b>	15pF Maximum
<b>Output Logic Type</b>	CMOS
<b>Control Voltage</b>	None (No Connect on Pin 1)
<b>Control Voltage Range</b>	0.0Vdc to Vdd
<b>Frequency Deviation</b>	±5ppm Minimum (Referenced to Fo at Vc=2.5Vdc; Vdd=5.0Vdc; over Operating Temperature Range)
<b>Linearity</b>	±10% Maximum
<b>Transfer Function</b>	Positive Transfer Characteristic
<b>Input Impedance</b>	10kOhms Typical
<b>Phase Noise</b>	-95dBc/Hz at 10Hz Offset -120dBc/Hz at 100Hz Offset -135dBc/Hz at 1kHz Offset -140dBc/Hz at 10kHz Offset (Measures at 12.800MHz)
<b>Start Up Time</b>	10mSec Maximum
<b>Storage Temperature Range</b>	-55°C to +125°C

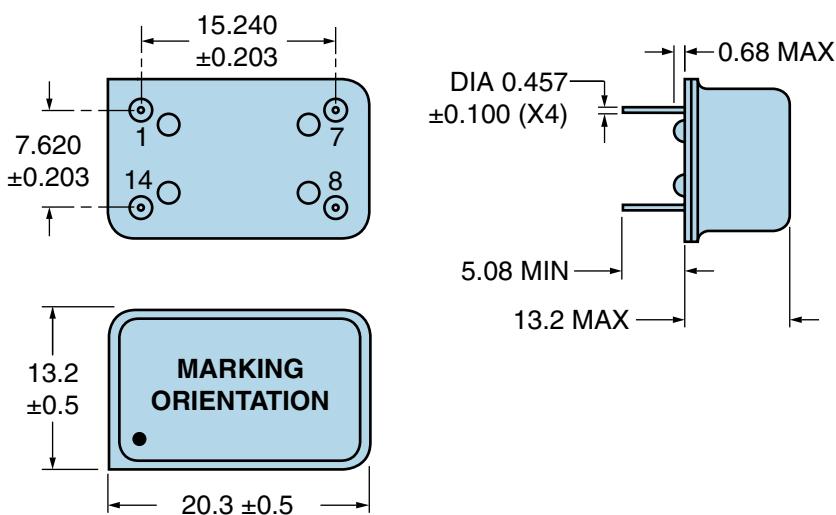
## ENVIRONMENTAL & MECHANICAL SPECIFICATIONS

<b>Gross Leak Test</b>	MIL-STD-883, Method 1014 Condition C
<b>Lead Integrity</b>	MIL-STD-883, Method 2004
<b>Mechanical Shock</b>	MIL-STD-202, Method 213 Condition C
<b>Resistance to Soldering Heat</b>	MIL-STD-202, Method 210
<b>Resistance to Solvents</b>	MIL-STD-202, Method 215
<b>Solderability</b>	MIL-STD-883, Method 2003
<b>Temperature Cycling</b>	MIL-STD-883, Method 1010
<b>Vibration</b>	MIL-STD-883, Method 2007 Condition A

# EB71F51C10AN2-16.000M



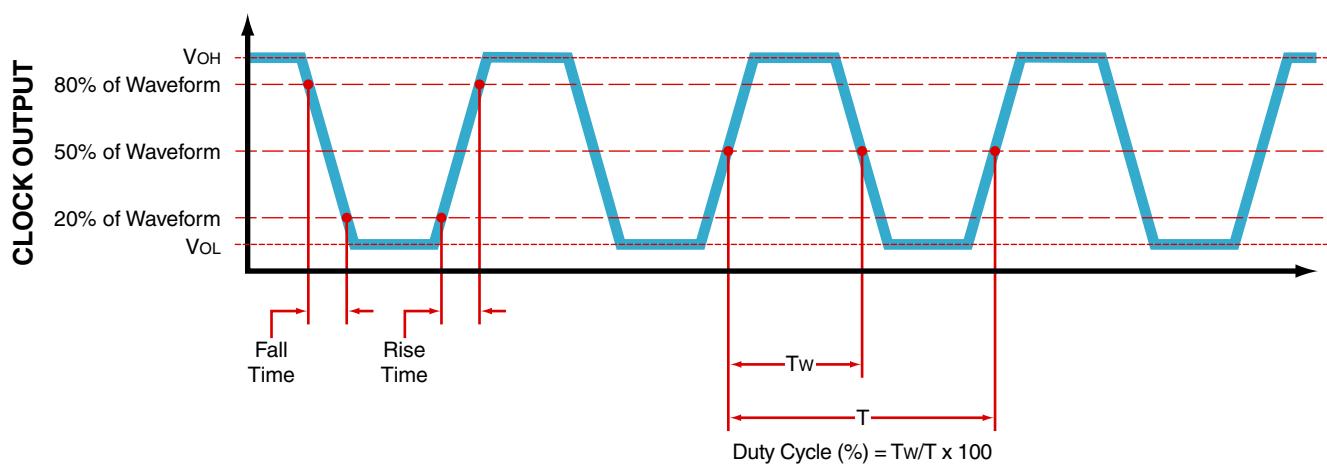
## MECHANICAL DIMENSIONS (all dimensions in millimeters)



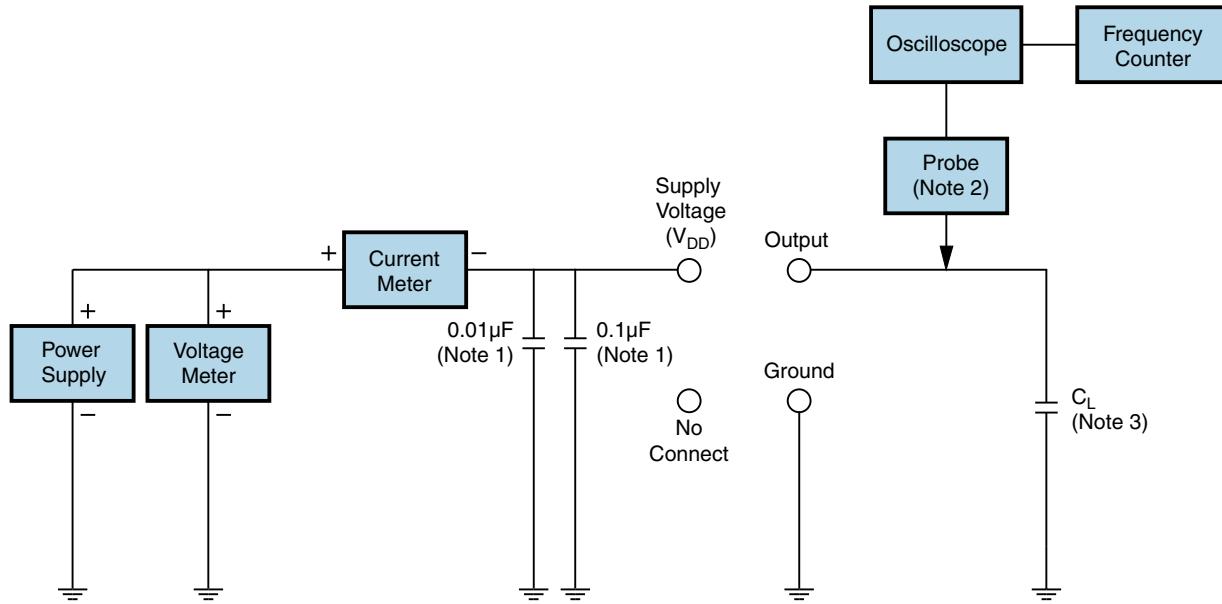
PIN	CONNECTION
1	No Connect
7	Case Ground
8	Output
14	Supply Voltage

LINE	MARKING
1	ECLIPTEK
2	16.000M
3	XXXXX XXXXXX=Ecliptek Manufacturing Identifier

## OUTPUT WAVEFORM



## Test Circuit for No Connect Option

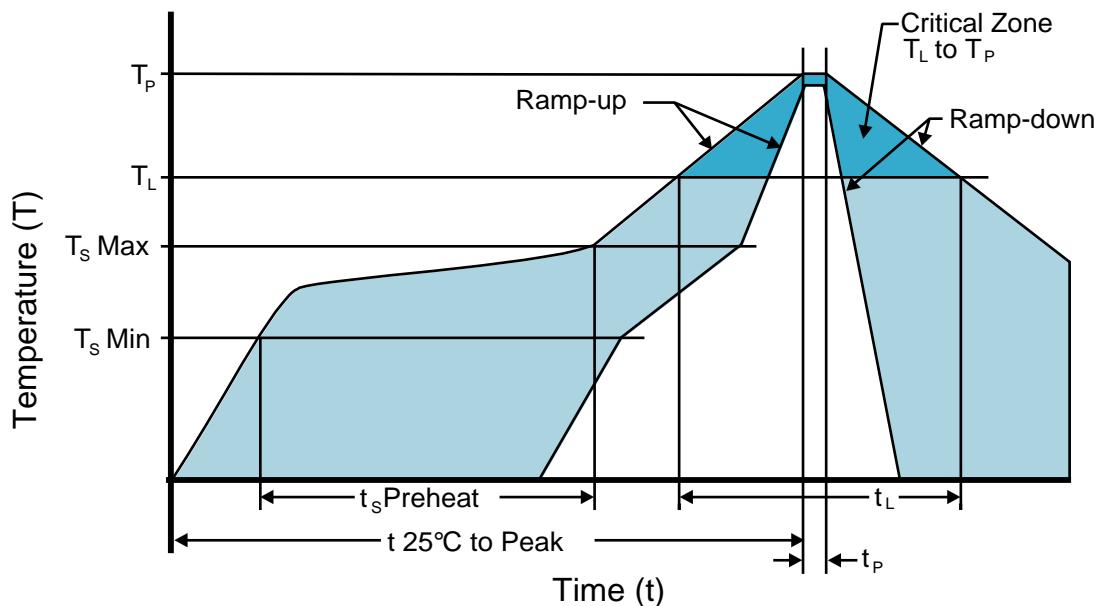


Note 1: An external  $0.01\mu\text{F}$  ceramic bypass capacitor in parallel with a  $0.1\mu\text{F}$  high frequency ceramic bypass capacitor close (less than 2mm) to the package ground and supply voltage pin is required.

Note 2: A low capacitance ( $<12\text{pF}$ ), 10X attenuation factor, high impedance ( $>10\text{Mohms}$ ), and high bandwidth ( $>300\text{MHz}$ ) passive probe is recommended.

Note 3: Capacitance value  $C_L$  includes sum of all probe and fixture capacitance.

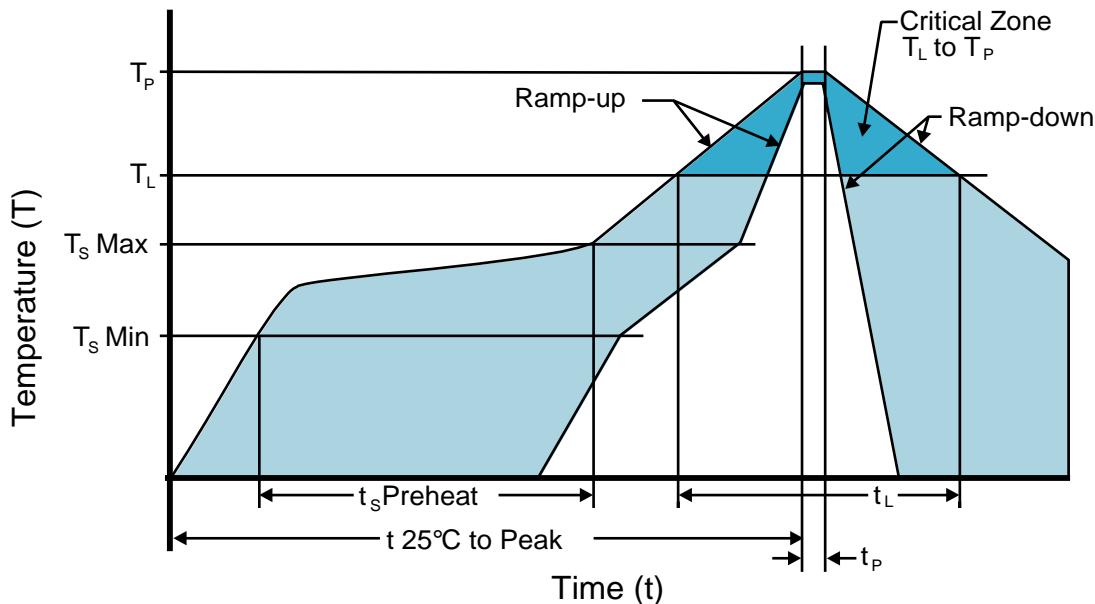
## Recommended Solder Reflow Methods



### Low Temperature Infrared/Convection 185°C

T <sub>s</sub> MAX to T <sub>L</sub> (Ramp-up Rate)	5°C/second Maximum
<b>Preheat</b>	
- Temperature Minimum (T <sub>s</sub> MIN)	N/A
- Temperature Typical (T <sub>s</sub> TYP)	150°C
- Temperature Maximum (T <sub>s</sub> MAX)	N/A
- Time (t <sub>s</sub> MIN)	60 - 120 Seconds
<b>Ramp-up Rate (T<sub>L</sub> to T<sub>P</sub>)</b>	5°C/second Maximum
<b>Time Maintained Above:</b>	
- Temperature (T <sub>L</sub> )	150°C
- Time (t <sub>L</sub> )	200 Seconds Maximum
<b>Peak Temperature (T<sub>P</sub>)</b>	185°C Maximum
<b>Target Peak Temperature (T<sub>P</sub> Target)</b>	185°C Maximum 2 Times
<b>Time within 5°C of actual peak (t<sub>p</sub>)</b>	10 seconds Maximum 2 Times
<b>Ramp-down Rate</b>	5°C/second Maximum
<b>Time 25°C to Peak Temperature (t)</b>	N/A
<b>Moisture Sensitivity Level</b>	Level 1
<b>Additional Notes</b>	Temperatures shown are applied to body of device. Use this method only for product with the Gull Wing option.

## Recommended Solder Reflow Methods



### Low Temperature Solder Bath (Wave Solder)

<b><math>T_S \text{ MAX to } T_L</math> (Ramp-up Rate)</b>	5°C/second Maximum
<b>Preheat</b>	
- Temperature Minimum ( $T_S \text{ MIN}$ )	N/A
- Temperature Typical ( $T_S \text{ TYP}$ )	150°C
- Temperature Maximum ( $T_S \text{ MAX}$ )	N/A
- Time ( $t_S \text{ MIN}$ )	30 - 60 Seconds
<b>Ramp-up Rate (<math>T_L</math> to <math>T_P</math>)</b>	5°C/second Maximum
<b>Time Maintained Above:</b>	
- Temperature ( $T_L$ )	150°C
- Time ( $t_L$ )	200 Seconds Maximum
<b>Peak Temperature (<math>T_P</math>)</b>	245°C Maximum
<b>Target Peak Temperature (<math>T_P</math> Target)</b>	245°C Maximum 1 Time / 235°C Maximum 2 Times
<b>Time within 5°C of actual peak (<math>t_P</math>)</b>	5 seconds Maximum 1 Time / 15 seconds Maximum 2 Times
<b>Ramp-down Rate</b>	5°C/second Maximum
<b>Time 25°C to Peak Temperature (t)</b>	N/A
<b>Moisture Sensitivity Level</b>	Level 1
<b>Additional Notes</b>	Temperatures shown are applied to back of PCB board and device leads only. Do not use this method for product with the Gull Wing option.

### Low Temperature Manual Soldering

185°C Maximum for 10 seconds Maximum, 2 times Maximum. (Temperatures listed are applied to device leads only. This method can be utilized with both Gull Wing and Non-Gull Wing devices.)

### High Temperature Manual Soldering

260°C Maximum for 5 seconds Maximum, 2 times Maximum. (Temperatures listed are applied to device leads only. This method can be utilized with both Gull Wing and Non-Gull Wing devices.)